

J604-VB Datasheet

P-Channel 60-V (D-S) MOSFET

PRODUCT SUMMARY		
V _{DS}	-60	V
$R_{DS(on)}$ $V_{GS} = 10$ V	19	mΩ
$R_{DS(on)}$ $V_{GS} = 4.5 V$	26	mΩ
I _D	-50	А
Configuration	Sin	gle

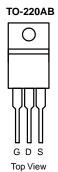
FEATURES

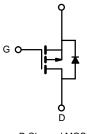
- TrenchFET[®] Power MOSFET
- 100 % UIS Tested

APPLICATIONS

Load Switch







P-Channel	MOSEET
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ABSOLUTE MAXIMUM RATING	S (T _A = 25 °C, unle	ess otherwise not	ed)	
Parameter		Symbol	Limit	Unit
Drain-Source Voltage		V _{DS}	- 60	V
Gate-Source Voltage		V _{GS}	± 20	v
	T _C = 25 °C		- 50	
Continuous Drain Current ($T_J = 150 \ ^\circ C$)	T _C = 70 °C		- 46	
	T _A = 25 °C	I _D	-39	
	T _A = 70 °C		-34	— A
Pulsed Drain Current		I _{DM}	- 200	
Avalanche Current Pulse	L = 0.1 mH	I _{AS}	- 45	
Single Pulse Avalanche Energy	L = 0.1 mH	E _{AS}	101	mJ
Continuous Courses Drain Diada Current	$T_{\rm C} = 25 ^{\circ}{\rm C}$	69 ^a		
Continuous Source-Drain Diode Current	T _A = 25 °C	I _S	20 ^b	— A
	T _C = 25 °C		104.2 ^a	
Mariana Dissisting	T _C = 70 °C		66.7 ^a	
Maximum Power Dissipation	T _A = 25 °C	P _D	3.1 ^b	W
	T _A = 70 °C		2 ^b	
Operating Junction and Storage Temperature Ra	ange	T _J , T _{stg}	- 55 to 150	°C

THERMAL RESISTANCE RATING	S				
Parameter		Symbol	Typical	Maximum	Unit
Maximum Junction-to-Ambient ^b	Steady State	R _{thJA}	33	40	°C/W
Maximum Junction-to-Case	Steady State	R _{thJC}	0.98	1.2	°C/vv

Notes:

<sup>a. Based on T_C = 25 °C.
b. Surface mounted on 1" x 1" FR4 board.</sup>

	SPECIFICATIONS ($T_J = 25 \ ^{\circ}C$,	unless othe	erwise noted)				
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	Static					-	
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 V, I_D = -250 \mu A$	- 60			V
	V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	I 250 uA		68		m\//°C
Gate-Source Leakage l_{QSS} $V_{DS} = 0$ $V_{QS} = 20$ ± 100 nA Zero Gate Voltage Drain Current l_{DSS} $V_{DS} = -60$ $V_{QS} = 0$ -1 μ A On-State Drain Current ^a $l_{D(on)}$ $V_{DS} = -60$ $V_{QS} = 0$ -10 μ A Drain-Source On-State Resistance ^a $R_{DS(on)}$ $V_{QS} = -10$ -10 A Forward Transconductance ^a g_{15} $V_{DS} = -50$ A 26 $m\Omega$ Dupti Capacitance C_{iss} $V_{DS} = -15$ V, $I_D = -50$ A 20 S Dupti Capacitance C_{iss} $V_{DS} = -30$ V, $V_{GS} = -10$ V, $I_D = -55$ A 76 115 Reverse Transfer Capacitance C_{iss} $V_{DS} = -30$ V, $V_{GS} = -10$ V, $I_D = -55$ A 76 115 Gate-Source Charge Q_{gd} $V_{DS} = -30$ V, $V_{GS} = -10$ V, $I_D = -55$ A 16 nC Gate Resistance R_g $f = 1$ MHz 5.2 Ω Ω Turn-Off Delay Time $I_d(on)$ $V_{DD} = -2$ V, $R_L = 2 \Omega$ 10 15 7 </td <td>V_{GS(th)} Temperature Coefficient</td> <td>$\Delta V_{GS(th)}/T_J$</td> <td>5</td> <td></td> <td>- 5.2</td> <td></td> <td></td>	V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	5		- 5.2		
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}, I_{D} = -250 \ \mu A$	- 1		- 3	V
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 \text{ V}, \text{ V}_{GS} = \pm 20 \text{ V}$			± 100	nA
$ \begin{array}{ c c c c c c c c c c c c c c c c c c c$	Zone Cote Maltana Durin Ourmant		$V_{DS} = -60 \text{ V}, \text{ V}_{GS} = 0 \text{ V}$			- 1	
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	Zero Gate voltage Drain Current	DSS	$V_{DS} = -60 \text{ V}, V_{GS} = 0 \text{ V}, T_{J} = 55 \text{ °C}$			- 10	μΑ
$\begin{array}{c c c c c c c c c c c c c c c c c c c $	On-State Drain Current ^a	I _{D(on)}	$V_{DS} = -5 V, V_{GS} = -10 V$	- 120			А
$\begin{array}{c c c c c c c c c c c c c c c c c c c $		Б	V _{GS} = - 10 V, I _D = - 30 A		19		m 0
	Drain-Source On-State Resistance	™DS(on)	V _{GS} = - 4.5 V, I _D = - 20 A		26		1115.2
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	Forward Transconductance ^a	9 _{fs}	V _{DS} = - 15 V, I _D = - 50 A	20			S
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	Dynamic ^b						
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	Input Capacitance	C _{iss}			3700		
$ \begin{array}{c c c c c c c c } Total Gate Charge & Q_{g} & V_{DS} = -30 \ V, \ V_{GS} = -10 \ V, \ I_{D} = -55 \ A & 76 & 115 \\ \hline & 38 & 60 \\ \hline & 38 & 60 \\ \hline & & 38 & 60 \\ \hline & & & & & & & & & & & & & & & & & &$	Output Capacitance	C _{oss}	$V_{DS} = -25 V$, $V_{GS} = 0 V$, f = 1 MHz		390		pF
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	Reverse Transfer Capacitance	C _{rss}			290		
$ \begin{array}{ c c c c c } \hline & & & & & & & & & & & & & & & & & & $	Total Cata Charge	0	V_{DS} = - 30 V, V_{GS} = - 10 V, I_{D} = - 55 A		76	115	
$\begin{array}{c c c c c c c c c } \hline Gate-Source Charge & Q_{gs} & V_{DS} = -30 \ V, \ V_{GS} = -4.5 \ V, \ I_D = -55 \ A & 16 & 19 & 19 & 19 & 19 & 19 & 19 & 10 & 15 & 19 & 10 & 15 & 10 & 10$	Total Gale Charge	۵g			38	60	
$ \begin{array}{c c c c c c c c c } \hline Gate Resistance & R_g & f = 1 \ \text{MHz} & 5.2 & \Omega \\ \hline Turn-On \ Delay \ Time & t_d(on) & \\ \hline Rise \ Time & t_r & \\ \hline Turn-Off \ Delay \ Time & t_d(off) & \\ \hline Fall \ Time & t_f & \\ \hline \hline Palar Source \ Body \ Diode \ Characteristics & \\ \hline Continuous \ Source-Drain \ Diode \ Current & I_S & T_C = 25 \ ^C & -69 & \\ \hline Pulse \ Diode \ Forward \ Current^a & I_{SM} & -150 & \\ \hline Pulse \ Diode \ Forward \ Current^a & I_{SM} & -150 & \\ \hline Body \ Diode \ Reverse \ Recovery \ Time & t_{rr} & \\ \hline Body \ Diode \ Reverse \ Recovery \ Fall \ Time & t_a & \\ \hline I_F = -50 \ A, \ di/dt = 100 \ A/\mus, \ T_J = 25 \ ^C & 29 & \\ \hline \end{array} $	Gate-Source Charge	Q _{gs}	V_{DS} = - 30 V, V_{GS} = - 4.5 V, I_{D} = - 55 A		16		nc
$\begin{array}{c c c c c c c c c c c c c c c c c c c $	Gate-Drain Charge	Q _{gd}			19		
$\begin{array}{c c c c c c c c c c c c c c c c c c c $	Gate Resistance	R _g	f = 1 MHz		5.2		Ω
$\begin{array}{c c c c c c c c c c c c c c c c c c c $	Turn-On Delay Time	t _{d(on)}			10	15	
$\begin{array}{c c c c c c c c c c c c c c c c c c c $	Rise Time	t _r	V_{DD} = - 2 V, R_L = 2 Ω		7	15	
Fall Time t_f 4060Drain-Source Body Diode CharacteristicsContinuous Source-Drain Diode Current I_S $T_C = 25 \ ^{\circ}C$ -69APulse Diode Forward Current ^a I_{SM} -150-150ABody Diode Voltage V_{SD} $I_S = -30 \ A$ -1-1.5VBody Diode Reverse Recovery Time t_{rr} $I_F = -50 \ A, di/dt = 100 \ A/\mus, T_J = 25 \ ^{\circ}C$ 59120nCReverse Recovery Fall Time t_a t_a $T_C = 25 \ ^{\circ}C$ 29ns	Turn-Off Delay Time	t _{d(off)}	$I_{D}\cong$ - 10 A, V_{GEN} = - 10 V, R_{g} = 1 Ω		70	110	- ns
Continuous Source-Drain Diode CurrentIs $T_C = 25 \ ^{\circ}C$ - 69APulse Diode Forward Current ^a IsM- 150- 150Body Diode Voltage V_{SD} $I_S = -30 \ A$ - 1- 1.5VBody Diode Reverse Recovery Time t_{rr} 4568nsBody Diode Reverse Recovery Charge Q_{rr} $I_F = -50 \ A, di/dt = 100 \ A/\mus, T_J = 25 \ ^{\circ}C$ 59120nCReverse Recovery Fall Time t_a t_a t_a t_a t_a t_a t_a	Fall Time				40	60	
Pulse Diode Forward Current ^a I SM-ABody Diode Voltage V_{SD} $I_S = -30 \text{ A}$ 1-1.5VBody Diode Reverse Recovery Time t_{rr} 45 68nsBody Diode Reverse Recovery Charge Q_{rr} $I_F = -50 \text{ A}$, di/dt = 100 A/µs, $T_J = 25 \text{ °C}$ 59120nCReverse Recovery Fall Time t_a t_a t_a t_a t_a t_a t_a	Drain-Source Body Diode Characteristic	s					
Pulse Diode Forward Current ^a I SM- 150Body Diode Voltage V_{SD} $I_S = -30 \text{ A}$ - 1- 1.5VBody Diode Reverse Recovery Time t_{rr} 4568nsBody Diode Reverse Recovery Charge Q_{rr} $I_F = -50 \text{ A}$, di/dt = 100 A/µs, $T_J = 25 \text{ °C}$ 59120nCReverse Recovery Fall Time t_a t_a t_a t_a t_a t_a t_a	Continuous Source-Drain Diode Current	ا _S	T _C = 25 °C			- 69	٨
Body Diode Reverse Recovery Time t_{rr} 4568nsBody Diode Reverse Recovery Charge Q_{rr} $I_F = -50 \text{ A}$, di/dt = 100 A/µs, $T_J = 25 \text{ °C}$ 59120nCReverse Recovery Fall Time t_a $I_F = -50 \text{ A}$, di/dt = 100 A/µs, $T_J = 25 \text{ °C}$ 29ns	Pulse Diode Forward Current ^a	I _{SM}				- 150	
Body Diode Reverse Recovery Charge Q_{rr} $I_F = -50 \text{ A}, di/dt = 100 \text{ A/}\mu\text{s}, T_J = 25 \text{ °C}$ 59120nCReverse Recovery Fall Time t_a	Body Diode Voltage	V _{SD}	I _S = - 30 A		- 1	- 1.5	V
Reverse Recovery Fall Time t_a $I_F = -50$ Å, $di/dt = 100$ Å/µs, $T_J = 25$ C 29	Body Diode Reverse Recovery Time	t _{rr}			45	68	ns
Reverse Recovery Fall Time t _a 29	Body Diode Reverse Recovery Charge	Q _{rr}	I = 50 A di/dt = 100 A/up T = 25 °C		59	120	nC
ns ns	Reverse Recovery Fall Time	ta	$F = -50 \text{ A}, \text{ al/at} = 100 \text{ A/}\mu\text{s}, T_{\text{J}} = 25 \text{ °C}$		29		
	Reverse Recovery Rise Time	t _b	1		16		ns

Notes:

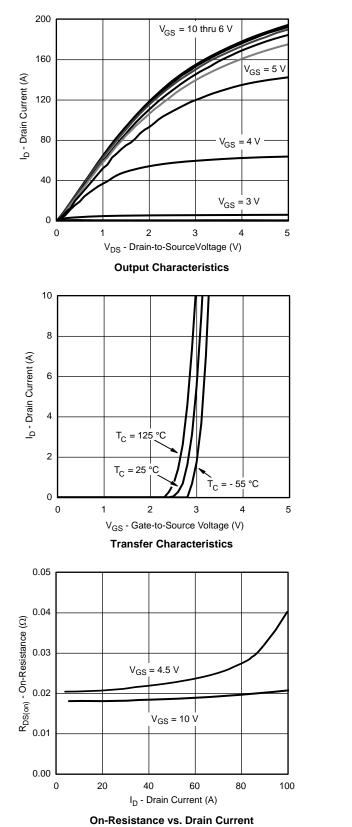
a. Pulse test; pulse width \leq 300 $\mu s,$ duty cycle \leq 2 %. b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

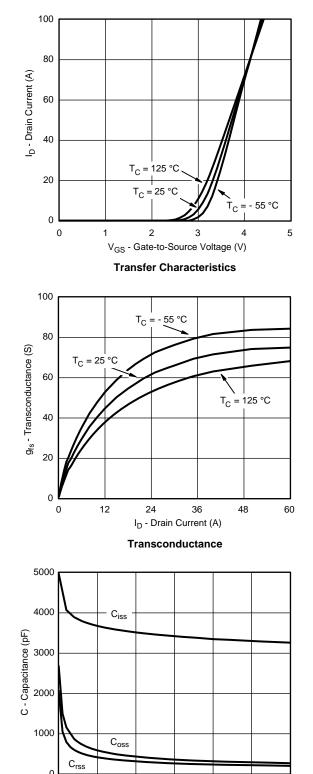
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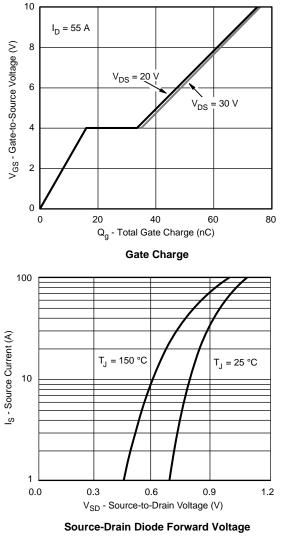


TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

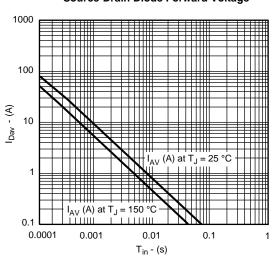


Capacitance

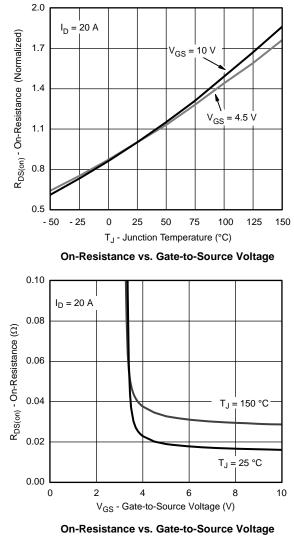


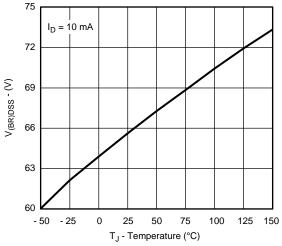


TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)



Single Pulse Avalanche Current Capability vs. Time

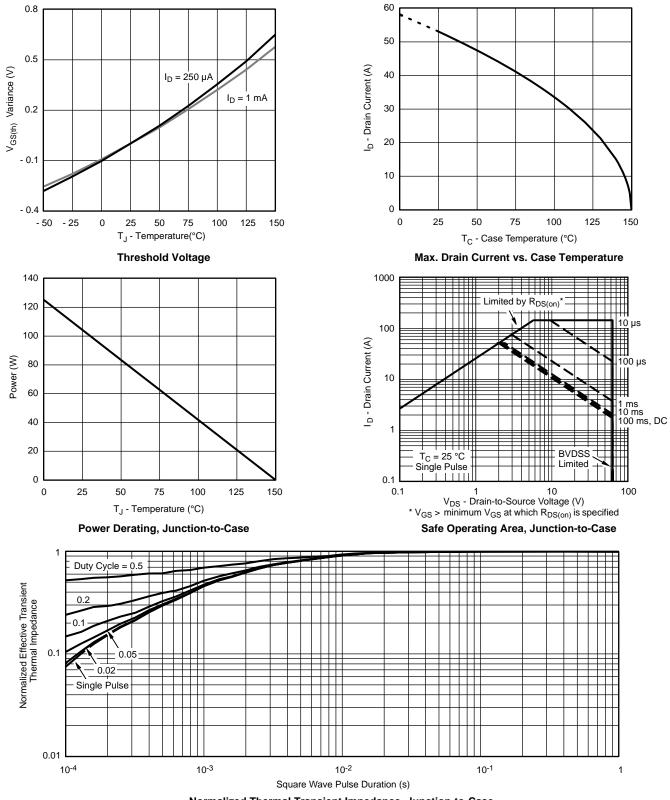




Drain-Source Breakdown Voltage vs. Junction Temperature



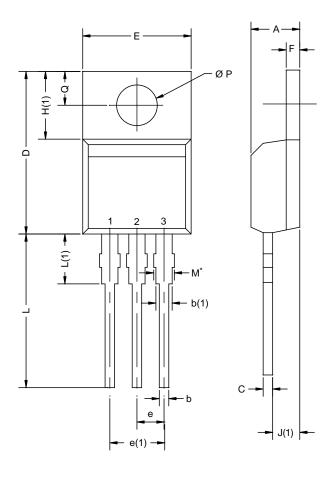




Normalized Thermal Transient Impedance, Junction-to-Case



TO-220AB



	MILLIN	IETERS	INCHES		
DIM.	MIN.	MAX.	MIN.	MAX.	
А	4.25	4.65	0.167	0.183	
b	0.69	1.01	0.027	0.040	
b(1)	1.20	1.73	0.047	0.068	
С	0.36	0.61	0.014	0.024	
D	14.85	15.49	0.585	0.610	
Е	10.04	10.51	0.395	0.414	
е	2.41	2.67	0.095	0.105	
e(1)	4.88	5.28	0.192	0.208	
F	1.14	1.40	0.045	0.055	
H(1)	6.09	6.48	0.240	0.255	
J(1)	2.41	2.92	0.095	0.115	
L	13.35	14.02	0.526	0.552	
L(1)	3.32	3.82	0.131	0.150	
ØΡ	3.54	3.94	0.139	0.155	
Q	2.60	3.00	0.102	0.118	

Notes

* M = 1.32 mm to 1.62 mm (dimension including protrusion) Heatsink hole for HVM



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